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Du, T.C.; Wong, J.; Lee, M.;
e-Commerce Technology, 2004. CEC 2004. Proceedings. IEEE International Conference on
6-9 July 2004 Page(s):170 - 177.
Digital Object Identifier 10.1109/ICECT.2004.1319731
AbstractPlus Full Text: PDF (263 KB) IEEE CNF |
| <input type="checkbox"/> | 2. Detecting and representing relevant Web deltas in WHOWEDA
Bhowmick, S.S.; Madria, S.K.; Wee Keong Ng;
Knowledge and Data Engineering, IEEE Transactions on
Volume 15, Issue 2, March-April 2003 Page(s):423 - 441
Digital Object Identifier 10.1109/TKDE.2003.1185843
AbstractPlus References Full Text: PDF (2779 KB) IEEE JNL |
| <input type="checkbox"/> | 3. Cost-benefit analysis of Web bag in a Web warehouse
Bhowmick, S.S.; Madria, S.; Wee-Kong Ng; Ee-Peng Lim;
Database Engineering and Applications, 1999. IDEAS '99. International Symposium Proceedings
2-4 Aug. 1999 Page(s):34 - 42
Digital Object Identifier 10.1109/IDEAS.1999.787249
AbstractPlus Full Text: PDF (188 KB) IEEE CNF |
| <input type="checkbox"/> | 4. Production datawarehouse and software toolset to support productivity improvement activiti
Saroia, M.; Halmel, S.;
Advanced Semiconductor Manufacturing Conference and Workshop, 1999 IEEE/SEMI
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